


<b>Search Notes</b>  	<b>Application/Control No.</b>  10585067	<b>Applicant(s)/Patent Under Reexamination</b>  TANAKA ET AL.
	<b>Examiner</b>  NICOLE M BUIE	<b>Art Unit</b>  1796

SEARCHED			
Class	Subclass	Date	Examiner
524	495	5/21/2009	NMB
	Updated above class/subclass search	12/4/2009	NMB
	Updated above class/subclass search	5/12/2010	NMB

SEARCH NOTES		
Search Notes	Date	Examiner
Inventor name search, PALM	5/21/2009	NMB
Reviewed related appln in eDAN 12/264089, 12/235021, 12/094775, 12/063331, 11/124262, 11/082479, 11/892729, 10/553976, 10/572779 (double patenting)	5/21/2009	NMB
EAST text search, see search history	5/21/2009	NMB
Updated inventor name search, PALM	12/4/2009	NMB
Updated invento name search, PALM	5/12/2010	NMB
EAST text search, see search history	5/12/2010	NMB

INTERFERENCE SEARCH			
Class	Subclass	Date	Examiner

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